

INFORMATION DISCLOSURE CITATION	ATTY. DOCKET NO.	SERIAL NO.
	<u>1035-499</u>	Unknown
	APPLICANT	
	<u>NAGATA et al.</u>	
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	<u>March 10, 2004</u>	2871

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

							TRANSLATION		
DOCUMENT		DATE		COUNTRY		CLASS	SUBCLASS	YES	NO
	3-288824 A	12-1991		JP				partial	
	4-212458 A	8-1992		JP				partial	
	9-152628 A	6-1997		JP				partial	
	0 602 475 A	6-1994		EP					
	0 523 783 A	1-1993		EP					
	0 783 177 A	7-1997		EP					
	58-172685 A	10-1983		JP				partial	
	60-160173 A	8-1985		JP				partial	

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

	den Boer et al, "25.1: Similarities Between TFT Arrays for Direct-Conversion X-Ray Sensors and High-Aperture AMLCDs", SID 98 DIGEST, 1998, pp. 371-374
	USSN 09/542,485, filed April 3, 2000 entitled "ACTIVE MATRIX SUBSTRATE, METHOD OF MANUFACTURING SAME AND FLAT-PANEL IMAGE SENSOR"
	USSN 09/239,855, filed January 29, 1999, entitled "TWO-DIMENSIONAL IMAGE DETECTING DEVICE AND MANUFACTURING METHOD THEREOF"
	USSN 09/229,269, filed January 13, 1999, entitled "TWO-DIMENSIONAL IMAGE DETECTOR AND PROCESS FOR MANUFACTURING THE SAME"
	"A new digital detector for projection radiography," (Denny L. Lee, et al., Proc. SPIE Vol. 2432, pp. 237-249, Medical Imaging 1995, May 1995)
	Japanese KOKAI (Published unexamined patent application) No. 342098/1994 (Tokukaihei 6-342098, Published December 13, 1994) -- with partial translation.
	"Application of a-Si Active Matrix Technology in a X-Ray Detector Panel", Jeromine et al, SID 97 DIGEST, May 13-15, 1997, pages 91-94.

*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

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	Patent Abstracts of Japan, vol. 016, no. 131 (P-1332), 3 April 1992 (1992-04-03) & JP 03 294824 A (NEC CORP), 26 December 1991 (1991-12-26)
	Patent Abstracts of Japan, vol. 017, no. 332 (P-1562), 23 June 1993 (1993-06-23) & JP 05 040271 A (NEC CORP), 19 February 1993 (1993-2-19)
	Den Boer et al., "Similarities Between TFT Arrays for Direct-Conversion X-ray Sensors and High-Aperture AMLCDs:, 1998 SID International Symposium, Digest of technical Papers, vol. 29, Proceedings of SID '98, International Symposium, Anaheim, CA, USA, 17-22 May 1998, pp. 371-374

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